

1. TYPE RUM002N02
 2. STRUCTURE SILICON N-CHANNEL MOS FET
 3. APPLICATIONS SWITCHING

4. ABSOLUTE MAXIMUM RATINGS [Ta=25°C]

DRAIN-SOURCE VOLTAGE	V_{DSS}	• • •	20V
GATE-SOURCE VOLTAGE	V_{GSS}	• • •	$\pm 8V$
DRAIN CURRENT CONTINUOUS	I_D	• • •	$\pm 200mA$
PULSED	I_{DP}	• • •	$\pm 400mA$ PW $\leq 10\mu s$ DUTY CYCLE $\leq 1\%$
TOTAL POWER DISSIPATION	P_D	• • •	150mW EACH TERMINAL MOUNTED ON A RECOMMENDED LAND
CHANNEL TEMPERATURE	T_{ch}	• • •	150°C
RANGE OF STORAGE TEMPERATURE	T_{stg}	• • •	-55~150°C

5. THERMAL RESISTANCE

CHANNEL TO AMBIENT	$R_{th(ch-a)}$	• • •	833°C/W EACH TERMINAL MOUNTED ON A RECOMMENDED LAND
--------------------	----------------	-------	---

DESIGN

CHECK

APPROVAL

DATE : 25/SEP/2008

SPECIFICATION No. TSQ03101-RUM002N02

*T. Arizono**A. Tsubaki**T. Komichi*

REV. : 0

ROHM CO., LTD.

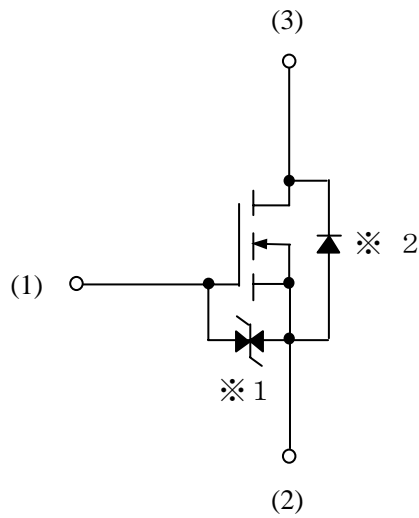
6.ELECTRICAL CHARACTERISTICS [Ta=25 °C]

PARAMETER	ITEM	CONDITION	MIN.	TYP.	MAX.
GATE-SOURCE LEAKAGE	I_{GSS}	$V_{GS} = \pm 8V / V_{DS} = 0V$	—	—	$\pm 10\mu A$
DRAIN-SOURCE BREAKDOWN VOLTAGE	$V_{(BR)DSS}$	$I_D = 1mA / V_{GS} = 0V$	20V	—	—
ZERO GATE VOLTAGE DRAIN CURRENT	I_{DSS}	$V_{DS} = 20V / V_{GS} = 0V$	—	—	1 μA
GATE THRESHOLD VOLTAGE	$V_{GS(th)}$	$V_{DS} = 10V / I_D = 1mA$	0.3V	—	1.0V
STATIC DRAIN-SOURCE ON-STATE RESISTANCE	$R_{DS(on)}$ * PULSED	$I_D = 200mA / V_{GS} = 2.5V$	—	0.8 Ω	1.2 Ω
		$I_D = 200mA / V_{GS} = 1.8V$	—	1.0 Ω	1.4 Ω
		$I_D = 40mA / V_{GS} = 1.5V$	—	1.2 Ω	2.4 Ω
		$I_D = 20mA / V_{GS} = 1.2V$	—	1.6 Ω	4.8 Ω
FORWARD TRANSFER ADMITTANCE	$ Y_{fs} $ * PULSED	$V_{DS} = 10V / I_D = 200mA$	200mS	—	—
INPUT CAPACITANCE	C_{iss}	$V_{DS} = 10V$ $V_{GS} = 0V$ $f = 1MHz$	—	25pF	—
OUTPUT CAPACITANCE	C_{oss}		—	10pF	—
REVERSE TRANSFER CAPACITANCE	C_{rss}		—	10pF	—
TURN-ON DELAY TIME	$t_{d(on)}$ * PULSED		$V_{DD} \doteq 10V$	—	5ns
RISE TIME	t_r * PULSED	$I_D = 150mA$ $V_{GS} = 4.0V$	—	10ns	—
TURN-OFF DELAY TIME	$t_{d(off)}$ * PULSED	$R_L \doteq 67\Omega$	—	15ns	—
FALL TIME	t_f * PULSED	$R_G = 10\Omega$ See Fig 1-1.1-2	—	10ns	—

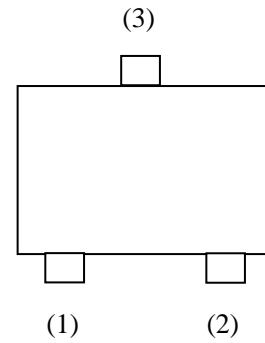
BODY DIODE CHARACTERISTICS (SOURCE-DRAIN)

PARAMETER	ITEM	CONDITION	MIN.	TYP.	MAX.
FORWARD VOLTAGE	V_{SD} * PULSED	$I_S = 100mA / V_{GS} = 0V$	—	—	1.2V

7. INNER CIRCUIT

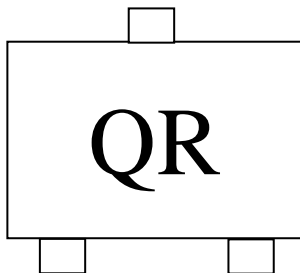


- (1) GATE
(2) SOURCE
(3) DRAIN



- ※ 1 ESD PROTECTION DIODE
※ 2 BODY DIODE

8. MARKING



“QR” MEANS RUM002N02.

9. MEASUREMENT CIRCUIT

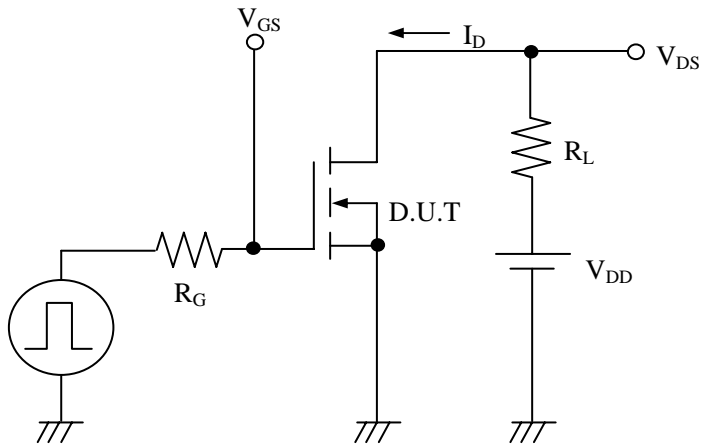


Fig.1-1 SWITCHING TIME MEASUREMENT CIRCUIT

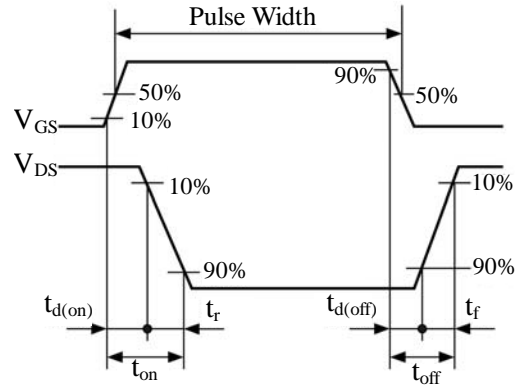


Fig.1-2 SWITCHING WAVEFORMS

10. Notice

This product might cause chip aging and breakdown under the large electrified environment.
Please consider to design ESD protection circuit.